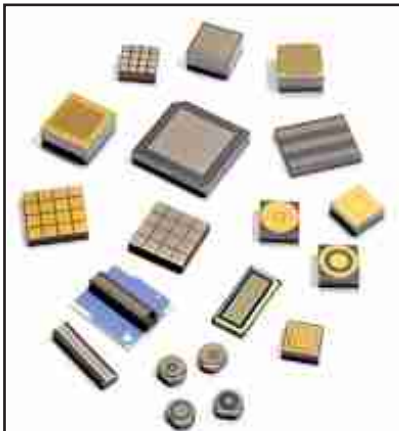


Planar Detector Grades



CdZnTe Radiation Detector ingots, slices, and tiles



Polished and metalized CdZnTe Radiation Detector tiles

Select Counter Grade

Peak/Valley:	3:1 @ 59.5 keV
Resolution:	25% (15 keV) @ 59.5 keV (FWHM)
Peak/Valley:	1.6:1 @ 122 keV

Discriminator Grade

Peak/Valley:	8:1 @ 59.5 keV
Resolution:	15% (9 keV) @ 59.5 keV (FWHM)
Peak/Valley:	2:1 @ 122 keV
Resolution:	6% (8 keV) @ 122 keV **

Select Discriminator Grade

Peak/Valley:	8:1 @ 59.5 keV
Resolution:	10% (6 keV) @ 59.5 keV (FWHM)
Peak/Valley:	3:1 @ 122 keV
Resolution:	6% (8 keV) @ 122 keV (FWHM)

Spectrometer Grade

Peak/Valley:	8:1 @ 59.5 keV
Resolution:	10% (6 keV) @ 59.5 keV (FWHM)
Peak/Valley:	3:1 @ 122 keV
Resolution:	6% (8 keV) @ 122 keV (FWHM)
Peak/Valley:	1.8:1 @ 662 keV
Resolution:	3% (20 keV) @ 662 keV **

** Defined as 2 x Upper Half Width at Half Maximum (UHWHM)

NOTE: Listed criteria apply to material of thickness from 1 to 5 mm. Typical measurements are performed with an applied field of between 100 and 200 Volts/mm of thickness, preamplifier shaping time of 0.25 - 2.0 μ s and an external ultra low noise preamplifier (eV-5093). Noise threshold for all classifications 10 keV.

Pixilated Detector Grades

High Electron Transport	$\mu\tau_e > 3 \times 10^3 \text{ cm}^2/\text{V}$
Medium Electron Transport	$\mu\tau_e > 1 \times 10^3 \text{ cm}^2/\text{V}$
Low Electron Transport	$\mu\tau_e < 1 \times 10^3 \text{ cm}^2/\text{V}$

NOTE: Electron transport properties determined using Alpha emitting source and fitting peak position verses bias voltage data to the Hecht equation. CZT Electron transport characterization is performed on an ingot basis and is not performed on individual parts unless specified. Detectors ordered with specific electron transport characteristics will be cut from known ingots meeting requested specification.